BLF8G10LS-270V; **BLF8G10LS-270GV**

Power LDMOS transistor

Rev. 1 — 3 December 2012

Product data sheet

1. Product profile

1.1 General description

270 W LDMOS power transistor with improved video bandwidth for base station applications at frequencies from 790 MHz to 960 MHz.

Table 1. Typical performance

Typical RF performance at T_{case} = 25 °C in a common source class-AB production test circuit, tested on straight lead device.

Test signal	f	V_{DS}	$P_{L(AV)}$	G_p	η_{D}	ACPR _{5M}
	(MHz)	(V)	(W)	(dB)	(%)	(dBc)
2-carrier W-CDMA	869 to 894	28	67	19.5	31	-37 <u>[1]</u>

^[1] Test signal: 3GPP test model 1; 64 DPCH; PAR = 8.4 dB at 0.01 % probability on CCDF; carrier spacing 10 MHz.

1.2 Features and benefits

- Excellent ruggedness
- High efficiency
- Low R_{th} providing excellent thermal stability
- Designed for broadband operation (790 MHz to 960 MHz)
- Lower output capacitance for improved performance in Doherty applications
- Decoupling leads to enable improved video bandwidth (55 MHz typical)
- Designed for low memory effects providing excellent pre-distortability
- Internally matched for ease of use
- Integrated ESD protection
- Design optimized for gull-wing and straight lead versions
- Compliant to Directive 2002/95/EC, regarding Restriction of Hazardous Substances (RoHS)

1.3 Applications

RF power amplifiers for W-CDMA base stations and multi carrier applications in the 790 MHz to 960 MHz frequency range



2. Pinning information

Table 2. Pinning

Pin	Description	Simplified outline	Graphic symbol
BLF8G10L	_S-270V (SOT1244B)		
1	drain		_
2	gate	4 1 5	6.7-1-4,5
3	source	[1]	6,7
4	decoupling lead	3	3
5	decoupling lead		aaa-003619
6	n.c.		
7	n.c.	6 2 7	
BLF8G10L	_S-270GV (SOT1244C)		
1	drain	4 4 5	4
2	gate	4 1 5	6,7 → 1
3	source	[1]	2
4	decoupling lead		3
5	decoupling lead	6 2 7	aaa-003619
6	n.c.	6 2 7	
7	n.c.		

^[1] Connected to flange.

3. Ordering information

Table 3. Ordering information

Type number	Packa	Package		
	Name	Description	Version	
BLF8G10LS-270V	-	earless flanged ceramic package; 6 leads	SOT1244B	
BLF8G10LS-270GV	-	earless flanged ceramic package; 6 leads	SOT1244C	

4. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
V_{DS}	drain-source voltage		-	65	V
V_{GS}	gate-source voltage		-0.5	+13	V
T _{stg}	storage temperature		-65	+150	°C
Tj	junction temperature		-	225	°C

5. Thermal characteristics

Table 5. Thermal characteristics

Symbol	Parameter	Conditions	Тур	Unit
$R_{th(j-c)}$	thermal resistance from junction to case	$T_{case} = 80 ^{\circ}C; P_{L} = 67 W$	0.257	K/W

6. Characteristics

Table 6. DC characteristics

 $T_i = 25$ °C; per section unless otherwise specified.

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Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$V_{(BR)DSS}$	drain-source breakdown voltage	$V_{GS} = 0 \text{ V}; I_D = 4.5 \text{ mA}$	65	-	-	V
$V_{GS(th)}$	gate-source threshold voltage	$V_{DS} = 10 \text{ V}; I_D = 450 \text{ mA}$	1.5	1.8	2.3	V
I _{DSS}	drain leakage current	$V_{GS} = 0 \text{ V}; V_{DS} = 28 \text{ V}$	-	-	4.2	μΑ
I _{DSX}	drain cut-off current	$V_{GS} = V_{GS(th)} + 3.75 \text{ V};$ $V_{DS} = 10 \text{ V}$	-	82	-	Α
I _{GSS}	gate leakage current	$V_{GS} = 11 \text{ V}; V_{DS} = 0 \text{ V}$	-	-	420	nΑ
9 _{fs}	forward transconductance	$V_{DS} = 10 \text{ V}; I_D = 450 \text{ mA}$	-	3.92	-	S
R _{DS(on)}	drain-source on-state resistance	$V_{GS} = V_{GS(th)} + 3.75 V;$ $I_D = 15.75 A$	-	0.04	-	Ω

Table 7. RF characteristics

Test signal: 2-carrier W-CDMA; PAR = 8.4 dB at 0.01 % probability on the CCDF; 3GPP test model 1; 1-64 DPCH; f_1 = 871.5 MHz; f_2 = 881.5 MHz; f_3 = 881.5 MHz; f_4 = 891.5 MHz; f_5 = 881.5 MHz; f_6 = 891.5 MHz; RF performance at V_{DS} = 28 V; I_{Dq} = 2000 mA; T_{case} = 25 °C; unless otherwise specified; in a class-AB production test circuit, tested on straight lead device.

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
G_p	power gain	$P_{L(AV)} = 67 \text{ W}$	17.3	19.5	-	dB
RLin	input return loss	$P_{L(AV)} = 67 \text{ W}$	-	-16	-12	dB
η_{D}	drain efficiency	$P_{L(AV)} = 67 \text{ W}$	26	31	-	%
ACPR _{5M}	adjacent channel power ratio (5 MHz)	$P_{L(AV)} = 67 \text{ W}$	-	-37	-33	dBc

7. Test information

7.1 Ruggedness in class-AB operation

The BLF8G10LS-270V and BLF8G10LS-270GV are capable of withstanding a load mismatch corresponding to VSWR = 10 : 1 through all phases under the following conditions: $V_{DS} = 28$ V; $I_{Dq} = 2000$ mA; $P_L = 270$ W; f = 820 MHz; f = 869 MHz; f = 960 MHz and a load mismatch corresponding to VSWR = 5 : 1 through all phases under the following conditions: $V_{DS} = 28$ V; $I_{Dq} = 2000$ mA; $P_L = 270$ W; f = 790 MHz.

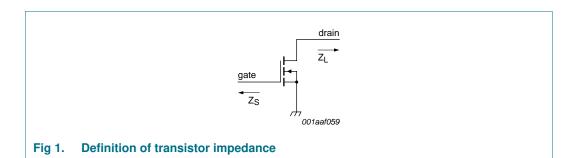
7.2 Impedance information

Table 8. Typical impedance

 I_{Dq} = 2700 mA; main transistor V_{DS} = 28 V.

24		
f	Z _S [1]	Z _L [1]
(MHz)	(Ω)	(Ω)
790	1.4 – j1.84	1.22 – j2.07
820	1.58 – j1.96	1.29 – j1.95
869	1.84 – j2.70	1.12 – j1.83
881	1.78 – j2.94	1.12 – j1.84
894	1.90 – j3.08	1.12 – j1.84
920	2.06 - j2.50	1.04 – j1.13
940	2.10 - j2.90	1.04 – j1.13
960	2.56 – j2.65	1.00 – j1.22

[1] Z_S and Z_L defined in Figure 1.



7.3 VBW in class-AB operation

The BLF8G10LS-270V and BLF8G10LS-270GV show 55 MHz (typical) video bandwidth in class-AB test circuit in 800 MHz band at V_{DS} = 28 V and I_{Dq} = 2 A.

7.4 Test circuit

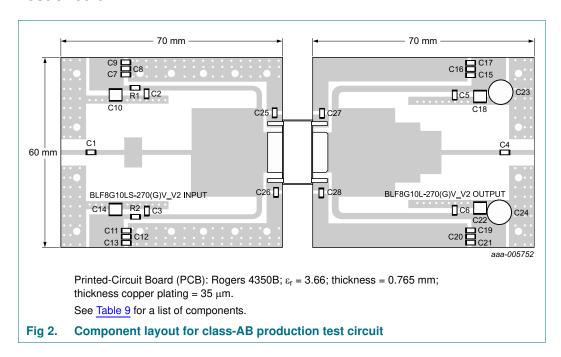


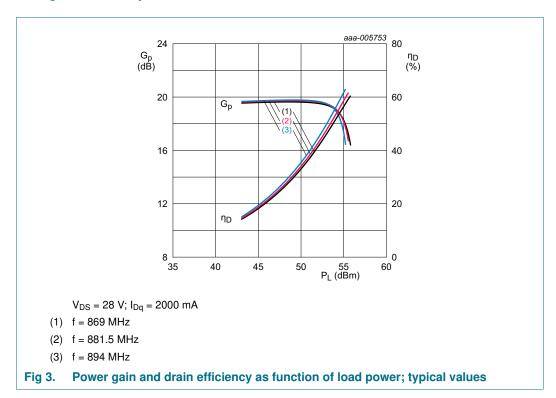
Table 9. List of components For test circuit see Figure 2.

Component	Description	Value		Remarks
C1, C4	multilayer ceramic chip capacitor	47 pF	[1]	ATC100B
C2, C3, C5, C6	multilayer ceramic chip capacitor	45 pF	[1]	ATC100B
C7, C11, C15, C19	multilayer ceramic chip capacitor	0.01 μF	[2]	Murata
C8, C12, C16, C20	multilayer ceramic chip capacitor	0.1 μF	[2]	Murata
C9, C13, C17, C21	multilayer ceramic chip capacitor	1 μF	[2]	Murata
C10, C14, C18, C22	multilayer ceramic chip capacitor	4.7 μF	[2]	Murata
C23, C24	electrolytic capacitor	470 μF, 63 V		
C25, C26, C27, C28	multilayer ceramic chip capacitor	10 μF	[2]	Murata
R1, R2	chip resistor	9.1 Ω	[3]	Vishay Dale 0805

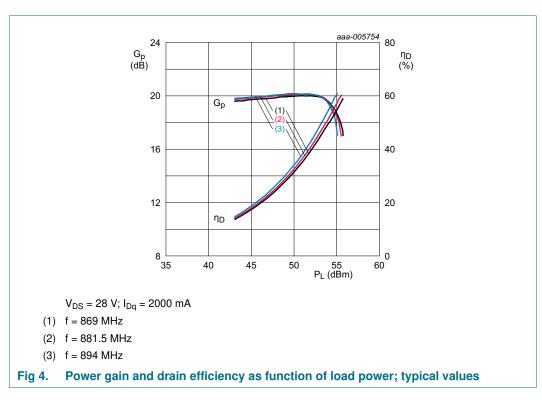
- [1] American Technical Ceramics type 100B or capacitor of same quality.
- [2] Murata or capacitor of same quality.
- [3] Vishay Dale resistor of same quality.

7.5 Graphical data

7.5.1 Straight lead sample CW

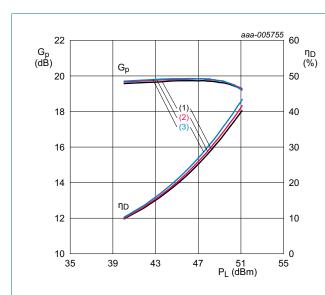


7.5.2 Straight lead sample CW pulsed



BLF8G10LS-270V_8G10LS-270GV

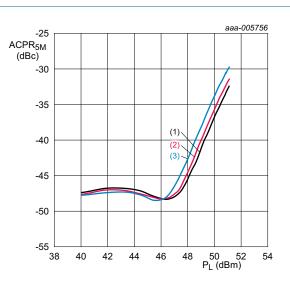
7.5.3 Straight lead sample 1-carrier W-CDMA



 $V_{DS} = 28 \text{ V}; I_{Dq} = 2000 \text{ mA}$

- (1) f = 869 MHz
- (2) f = 881.5 MHz
- (3) f = 894 MHz

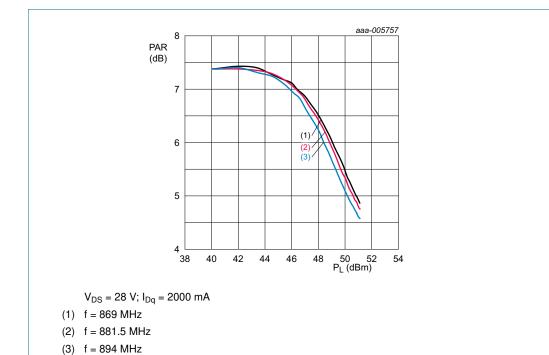
Fig 5. Power gain and drain efficiency as function of load power; typical values



 $V_{DS} = 28 \text{ V}; I_{Dq} = 2000 \text{ mA}$

- (1) f = 869 MHz
- (2) f = 881.5 MHz
- (3) f = 894 MHz

Fig 6. Adjacent channel power ratio (5 MHz) as a function of load power; typical values

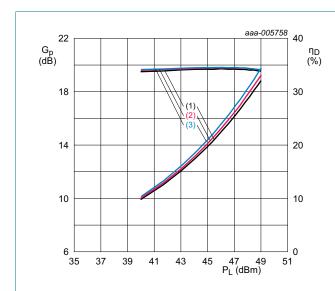


Peak-to-average ratio as a function of load power; typical values

BLF8G10LS-270V_8G10LS-270GV

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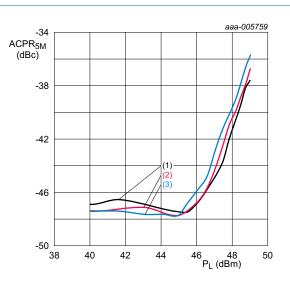
7.5.4 Straight lead sample 2-carrier W-CDMA



 $V_{DS} = 28 \text{ V}; I_{Dq} = 2000 \text{ mA}$

- (1) f = 869 MHz
- (2) f = 881.5 MHz
- (3) f = 894 MHz

Fig 8. Power gain and drain efficiency as function of load power; typical values

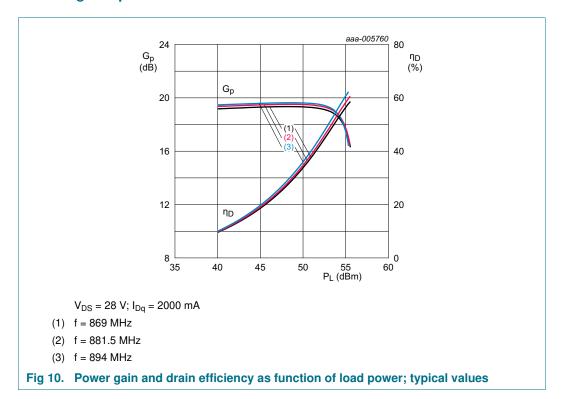


 $V_{DS} = 28 \text{ V}; I_{Dq} = 2000 \text{ mA}$

- (1) f = 869 MHz
- (2) f = 881.5 MHz
- (3) f = 894 MHz

Fig 9. Adjacent channel power ratio (5 MHz) as a function of load power; typical values

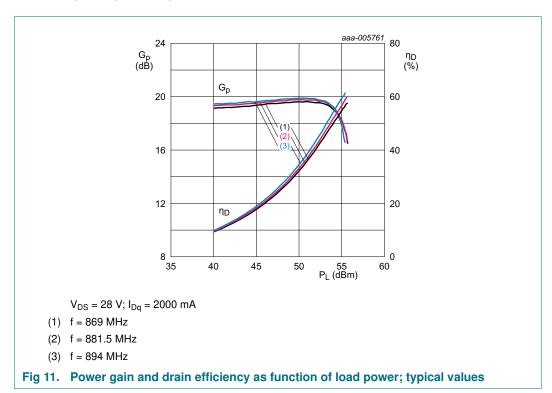
7.5.5 Gull-wing sample CW



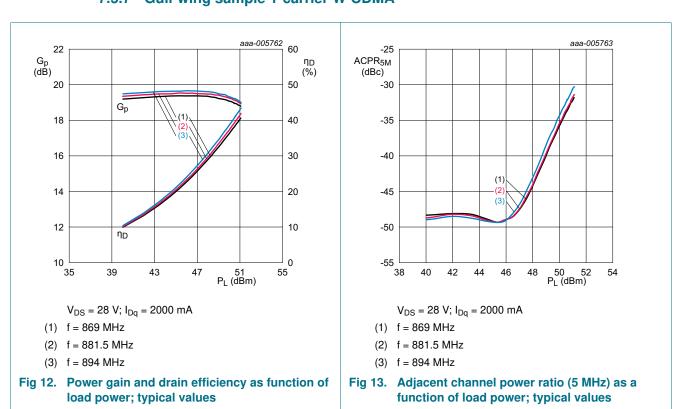
BLF8G10LS-270V_8G10LS-270GV

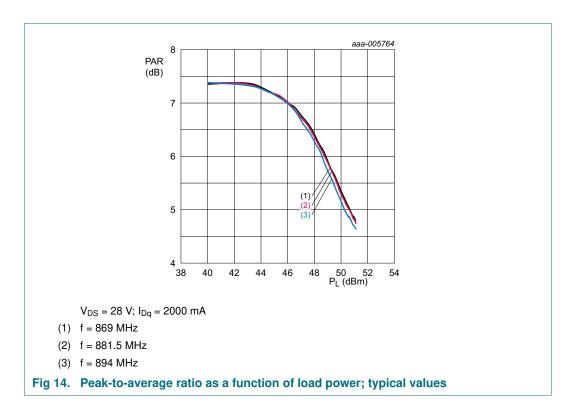
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7.5.6 Gull-wing sample CW pulsed

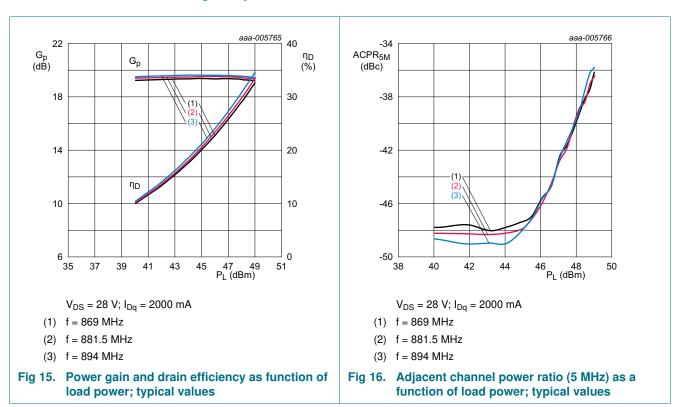


7.5.7 Gull-wing sample 1-carrier W-CDMA

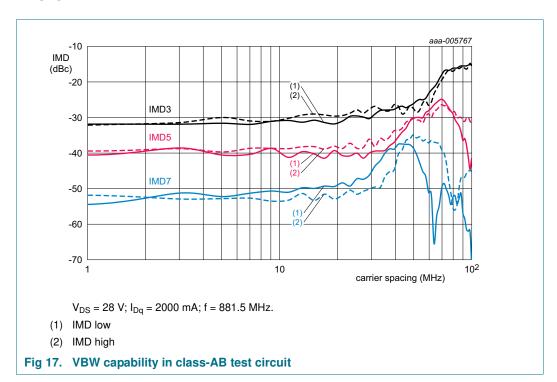




7.5.8 Gull-wing sample 2-carrier W-CDMA



7.5.9 2-Tone VBW



8. Package outline

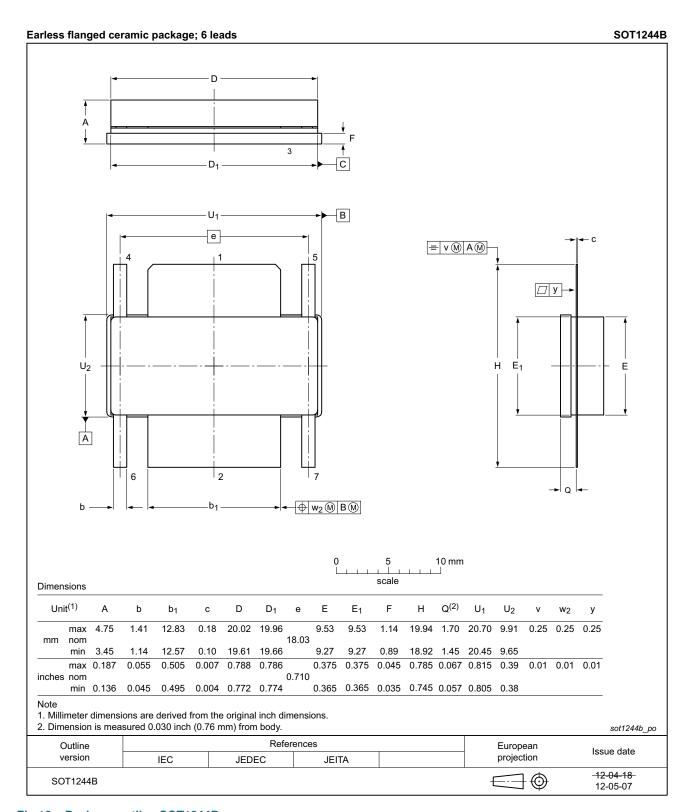


Fig 18. Package outline SOT1244B

BLF8G10LS-270V_8G10LS-270GV

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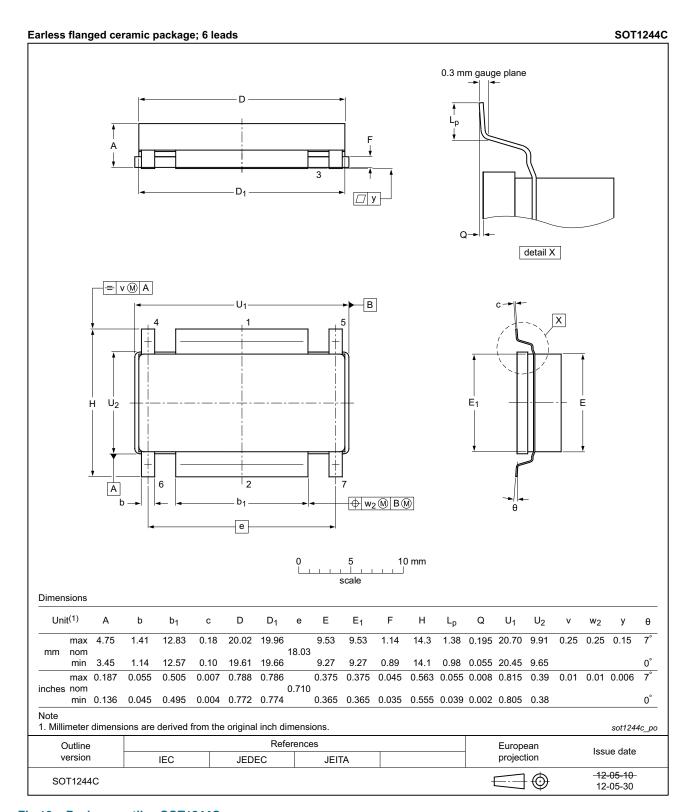


Fig 19. Package outline SOT1244C

9. Handling information

CAUTION



This device is sensitive to ElectroStatic Discharge (ESD). Observe precautions for handling electrostatic sensitive devices.

Such precautions are described in the ANSI/ESD S20.20, IEC/ST 61340-5, JESD625-A or equivalent standards.

10. Abbreviations

Table 10. Abbreviations

1000	
Acronym	Description
3GPP	3rd Generation Partnership Project
CCDF	Complementary Cumulative Distribution Function
CW	Continuous Wave
DPCH	Dedicated Physical Channel
ESD	ElectroStatic Discharge
IMD	InterModulation Distortion
LDMOS	Laterally Diffused Metal Oxide Semiconductor
PAR	Peak-to-Average Ratio
VBW	Video BandWidth
VSWR	Voltage Standing Wave Ratio
W-CDMA	Wideband Code Division Multiple Access

11. Revision history

Table 11. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes
BLF8G10LS-270V_8G10LS-270GV v.1	20121203	Product data sheet	-	-

12. Legal information

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Power LDMOS transistor

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